

1/21/2013



**PRODUCT RELIABILITY REPORT
FOR**

MAXQ614

Maxim Integrated

**14460 Maxim Dr.
Dallas, TX 75244**

Approved by:

**Don Lipps
Manager, Reliability Engineering**

Conclusion:

The following qualification successfully meets the quality and reliability standards required of all Maxim Integrated products:

MAXQ614

In addition, Maxim Integrated's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at <http://www.maximintegrated.com/qa/reliability/monitor>.

Device Description:

A description of this device can be found in the product data sheet. You can find the product data sheet at <http://www.maximintegrated.com/search/parts.mvp>.

Reliability Derating:

The Arrhenius model will be used to determine the acceleration factor for failure mechanisms that are temperature accelerated.

$$AfT = \exp((Ea/k) * (1/Tu - 1/Ts)) = tu/ts$$

AfT = Acceleration factor due to Temperature
tu = Time at use temperature (e.g. 55°C)
ts = Time at stress temperature (e.g. 125°C)
k = Boltzmann's Constant (8.617 x 10⁻⁵ eV/°K)
Tu = Temperature at Use (°K)
Ts = Temperature at Stress (°K)
Ea = Activation Energy (e.g. 0.7 eV)

The activation energy of the failure mechanism is derived from either internal studies or industry accepted standards, or activation energy of 0.7eV will be used whenever actual failure mechanisms or their activation energies are unknown. All deratings will be done from the stress ambient temperature to the use ambient temperature.

An exponential model will be used to determine the acceleration factor for failure mechanisms, which are voltage accelerated.

$$AfV = \exp(B * (Vs - Vu))$$

AfV = Acceleration factor due to Voltage
Vs = Stress Voltage (e.g. 7.0 volts)
Vu = Maximum Operating Voltage (e.g. 5.5 volts)
B = Constant related to failure mechanism type (e.g. 1.0, 2.4, 2.7, etc.)

The Constant, B, related to the failure mechanism is derived from either internal studies or industry accepted standards, or a B of 1.0 will be used whenever actual failure mechanisms or their B are unknown. All deratings will be done from the stress voltage to the maximum operating voltage. Failure rate data from the operating life test is reported using a Chi-Squared statistical model at the 60% or 90% confidence level (Cf).

The failure rate, Fr, is related to the acceleration during life test by:

$$Fr = X / (ts * AfV * AfT * N * 2)$$

X = Chi-Sq statistical upper limit
N = Life test sample size

Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

$$MTTF = 1/Fr$$

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this device/process is:

FAILURE RATE: **MTTF (YRS):** **94920** **FITS:** **1.2**
DEVICE HOURS: **761891058** **FAILS:** **0**

Only data from Operating Life or similar stresses are used for this calculation.

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **B: 0** **Tu: 25 °C** **Vu: 3.6 Volts**

The reliability data follows. At the start of this data is the device information. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available and may contain some generic data. **Bold** Product Number denotes specific product data.

Device Information:

Process: TSMC 0.18um Mixed signal, Embedded Flash, General Purpose, Two Poly Five Metal, 1.8V/3.3V Polyimide - No
 Passivation: SiO/SiN
 Die Size: 78 x 80
 Number of Transistors: 28534110
 Interconnect: Aluminum / 0.5% Copper
 Gate Oxide Thickness: 32 Å

ESD CDM

DESCRIPTION	DATE CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
ESD SENSITIVITY	1329 MAXQ614 GW123527A	JESD22-C101 CDM 250 VOLTS	3 PUL'S	5	0	
ESD SENSITIVITY	1329 MAXQ614 GW123527A	JESD22-C101 CDM 500 VOLTS	3 PUL'S	5	1	No FA
ESD SENSITIVITY	1329 MAXQ614 GW123527A	JESD22-C101 CDM 750 VOLTS	3 PUL'S	5	1	No FA
Total:					2	

ESD HBM

DESCRIPTION	DATE CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
ESD SENSITIVITY	1103 MAXQ618 ZJ112624AB-	JESD22-A114 HBM 500 VOLTS	1 PUL'S	5	0	
ESD SENSITIVITY	1103 MAXQ618 ZJ112624AB-	JESD22-A114 HBM 1000 VOLTS	1 PUL'S	5	0	
ESD SENSITIVITY	1103 MAXQ618 ZJ112624AB-	JESD22-A114 HBM 1500 VOLTS	1 PUL'S	5	0	
ESD SENSITIVITY	1103 MAXQ618 ZJ112624AB-	JESD22-A114 HBM 2000 VOLTS	1 PUL'S	5	0	
ESD SENSITIVITY	1103 MAXQ618 ZJ112624AB-	JESD22-A114 HBM 2500 VOLTS	1 PUL'S	5	0	
Total:					0	

LATCH-UP

DESCRIPTION	DATE	CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
LATCH-UP I	1103	MAXQ618	ZJ112624AB- JESD78A, I-TEST 25C 100mA		6	0	
LATCH-UP I	1103	MAXQ618	ZJ112624AB- JESD78A, I-TEST 25C 250mA		6	0	
LATCH-UP V	1103	MAXQ618	ZJ112624AB- JESD78A, V-SUPPLY TEST 25C		6	0	
				Total:		0	

OPERATING LIFE

DESCRIPTION	DATE	CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
HIGH TEMP OP LIFE	0814	MAXQ1103	QN089294A 125C, 3.6V (PSA) & 2.0V (PSB)	1000 HRS	77	0	
HIGH TEMP OP LIFE	0828	MAXQ2010	QK086138C 125C, 3.6 VOLTS	1000 HRS	76	0	
HIGH TEMP OP LIFE	0851	MAXQ3108	QJ091011AC 125C, 3.6 VOLTS	192 HRS	73	0	
HIGH TEMP OP LIFE	0851	MAXQ610	QJ091123AB 125C, 3.6V (PSA) & 2.0V (PSB)	1000 HRS	77	0	
HIGH TEMP OP LIFE	0852	MAXQ1850	QJ091074AA 125C, 3.6 VOLTS	192 HRS	75	0	
HIGH TEMP OP LIFE	0906	MAXQ61H	QJ091049AB 125C, 3.6 VOLTS	192 HRS	45	0	
HIGH TEMP OP LIFE	0909	MAXQ8913	NQQ8ZAD 125C, 3.6V (PSA) & 5.0V (PSB)	192 HRS	77	0	
HIGH TEMP OP LIFE	0934	MAXQ1103	QN101437A 125C, 3.6V (PSA) & 2.0V (PSB)	192 HRS	77	0	
HIGH TEMP OP LIFE	0946	MAXQ622	QN091481C 125C, 3.6V (PSA) & 5.5V (PSB)	192 HRS	77	0	
HIGH TEMP OP LIFE	0951	MAXQ61C	QJ101202AC 125C, 3.6 VOLTS	192 HRS	45	0	
HIGH TEMP OP LIFE	1006	MAXQ1004	QS101775AB 125C, 3.6V (PSA) & 5.0V (PSB)	192 HRS	45	0	
HIGH TEMP OP LIFE	1011	MAXQ3103	QJ101246AB 125C, 3.6 VOLTS	192 HRS	48	0	
HIGH TEMP OP LIFE	1011	MAXQ3103	QJ101246AB 125C, 3.6 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	1024	MAXQ1010	QJ101790AG 125C, 5.5V (PS1) & 3.6V (PS2)	192 HRS	45	0	
HIGH TEMP OP LIFE	1030	MAXQ613	QJ101861CH 135C, 3.6 V (PSA)	192 HRS	45	0	
HIGH TEMP OP LIFE	1050	MAXQ6831	ZN112250BC 125C, 3.6V (PSA), 1.89V (PSB) & 2.94V (PSD)	1000 HRS	48	0	
HIGH TEMP OP LIFE	1111	MAXQ618	ZJ112624AD 125C, 3.6 VOLTS	192 HRS	48	0	
HIGH TEMP OP LIFE	1119	MAXQ1740	ZJ112746BA 125C, 3.6 VOLTS	192 HRS	48	0	
HIGH TEMP OP LIFE	1134	MAXQ1050	ZS123062AB 125C, 5.5V (PSA) & 3.6V (PSB)	192 HRS	48	0	
HIGH TEMP OP LIFE	1135	MAXQ610	ZJ111435FC- 125C, 3.6V (PSA) & 2.0V (PSB)	1000 HRS	77	0	

HIGH TEMP OP LIFE	1135	MAXQ610	ZJ111435BD	125C, 3.6V (PSA) & 2.0V (PSB)	1000 HRS	77	0
HIGH TEMP OP LIFE	1135	MAXQ610	ZJ111438BB-	125C, 3.6V (PSA) & 2.0V (PSB)	1000 HRS	77	0
HIGH TEMP OP LIFE	1211	MAXQ615	ZS123275AE	125C, 3.6 VOLTS	192 HRS	80	0
HIGH TEMP OP LIFE	1223	MAXQ1011	GW123374A	125C, 5.5V (PS1) & 3.6V (PS2)	1000 HRS	48	0

Total: 0

FAILURE RATE: MTTF (YRS): 94920 FITS: 1.2
DEVICE HOURS: 761891058 FAILS: 0

The MAXQ614 is qualified by extension of the MAXQ618. The MAXQ614 is built using the same die as MAXQ618 with a minor metal modification to allow identical scan chain testing. This is due to the MAXQ614 WLP package having reduced external connections (25) from MAXQ618 package (44).